

International
IR Rectifier

IRF7523D1

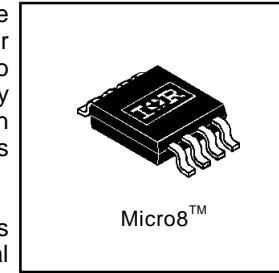
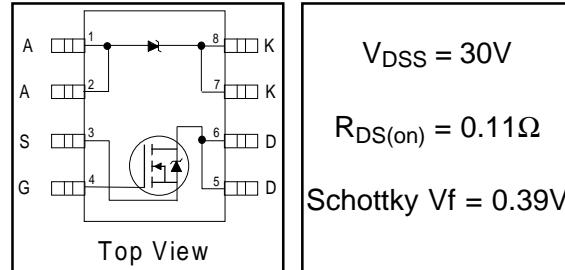
FETKY™ MOSFET / Schottky Diode

- Co-packaged HEXFET® Power MOSFET and Schottky Diode
- N-Channel HEXFET
- Low V_F Schottky Rectifier
- Generation 5 Technology
- Micro8™ Footprint

Description

The FETKY™ family of co-packaged HEXFETs and Schottky diodes offer the designer an innovative board space saving solution for switching regulator applications. Generation 5 HEXFETs utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. Combining this technology with International Rectifier's low forward drop Schottky rectifiers results in an extremely efficient device suitable for use in a wide variety of portable electronics applications like cell phone, PDA, etc.

The new Micro8™ package, with half the footprint area of the standard SO-8, provides the smallest footprint available in an SOIC outline. This makes the Micro8™ an ideal device for applications where printed circuit board space is at a premium. The low profile (<1.1mm) of the Micro8™ will allow it to fit easily into extremely thin application environments such as portable electronics and PCMCIA cards.



Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Parameter	Maximum	Units
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ④	A
$I_D @ T_A = 70^\circ C$		
I_{DM}	21	
$P_D @ T_A = 25^\circ C$	Power Dissipation ④	W
$P_D @ T_A = 70^\circ C$		
V_{GS}	10	W/°C
V_{GS}	± 20	V
dv/dt	Peak Diode Recovery dv/dt ②	V/ns
T_J, T_{STG}	-55 to +150	°C

Thermal Resistance Ratings

Parameter	Maximum	Units
$R_{θJA}$	100	°C/W

Notes:

- ① Repetitive rating; pulse width limited by maximum junction temperature (see figure 11)
- ② $I_{SD} \leq 1.7A$, $di/dt \leq 120A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 150^\circ C$
- ③ Pulse width $\leq 300\mu s$; duty cycle $\leq 2\%$
- ④ When mounted on 1 inch square copper board to approximate typical multi-layer PCB thermal resistance

MOSFET Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Parameter		Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	30	—	—	V	$V_{\text{GS}} = 0\text{V}$, $I_D = 250\mu\text{A}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	0.090	0.130	Ω	$V_{\text{GS}} = 10\text{V}$, $I_D = 1.7\text{A}$ ③
		—	0.140	0.190		$V_{\text{GS}} = 4.5\text{V}$, $I_D = 0.85\text{A}$ ③
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	1.0	—	—	V	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250\mu\text{A}$
g_f	Forward Transconductance	1.9	—	—	S	$V_{\text{DS}} = 10\text{V}$, $I_D = 0.85\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{\text{DS}} = 24\text{V}$, $V_{\text{GS}} = 0\text{V}$
		—	—	25		$V_{\text{DS}} = 24\text{V}$, $V_{\text{GS}} = 0\text{V}$, $T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	-100	nA	$V_{\text{GS}} = -20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	100		$V_{\text{GS}} = 20\text{V}$
Q_g	Total Gate Charge	—	7.8	12	nC	$I_D = 1.7\text{A}$
Q_{gs}	Gate-to-Source Charge	—	1.2	1.8		$V_{\text{DS}} = 24\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	2.5	3.8		$V_{\text{GS}} = 10\text{V}$ (see figure 6) ③
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	4.7	—	ns	$V_{\text{DD}} = 15\text{V}$
t_r	Rise Time	—	10	—		$I_D = 1.7\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	12	—		$R_G = 6.1\Omega$
t_f	Fall Time	—	5.3	—		$R_D = 8.7\Omega$ ③
C_{iss}	Input Capacitance	—	210	—	pF	$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	80	—		$V_{\text{DS}} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	32	—		$f = 1.0\text{MHz}$ (see figure 5)

MOSFET Source-Drain Ratings and Characteristics

Parameter		Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	1.25	A	
I_{SM}	Pulsed Source Current (Body Diode)	—	—	21		
V_{SD}	Body Diode Forward Voltage	—	—	1.2	V	$T_J = 25^\circ\text{C}$, $I_S = 1.7\text{A}$, $V_{\text{GS}} = 0\text{V}$
t_{rr}	Reverse Recovery Time (Body Diode)	—	40	60	ns	$T_J = 25^\circ\text{C}$, $I_F = 1.7\text{A}$
Q_{rr}	Reverse Recovery Charge	—	48	72	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③

Schottky Diode Maximum Ratings

	Parameter	Max.	Units	Conditions	
$I_{\text{F(av)}}$	Max. Average Forward Current	1.9	A	50% Duty Cycle. Rectangular Wave, $T_A = 25^\circ\text{C}$	
		1.3		$T_A = 70^\circ\text{C}$	
I_{SM}	Max. peak one cycle Non-repetitive Surge current	120	A	5μs sine or 3μs Rect. pulse	Following any rated load condition & with V_{RRM} applied
		11		10ms sine or 6ms Rect. pulse	

Schottky Diode Electrical Specifications

	Parameter	Max.	Units	Conditions	
V_{FM}	Max. Forward voltage drop	0.50	V	$I_F = 1.0\text{A}$, $T_J = 25^\circ\text{C}$	
		0.62		$I_F = 2.0\text{A}$, $T_J = 25^\circ\text{C}$	
		0.39		$I_F = 1.0\text{A}$, $T_J = 125^\circ\text{C}$	
		0.57		$I_F = 2.0\text{A}$, $T_J = 125^\circ\text{C}$	
I_{RM}	Max. Reverse Leakage current	0.06	mA	$V_R = 30\text{V}$	$T_J = 25^\circ\text{C}$
		16			$T_J = 125^\circ\text{C}$
C_t	Max. Junction Capacitance	92	pF	$V_R = 5\text{Vdc}$ (100kHz to 1 MHz) 25°C	
dv/dt	Max. Voltage Rate of Change	3600	V/μs	Rated V_R	

Power Mosfet Characteristics

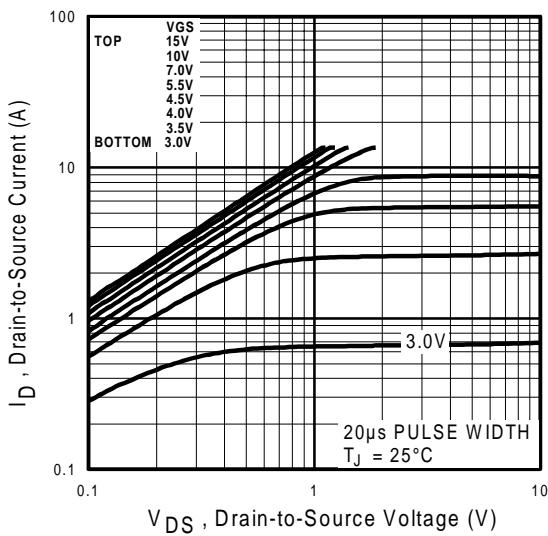


Fig 1. Typical Output Characteristics

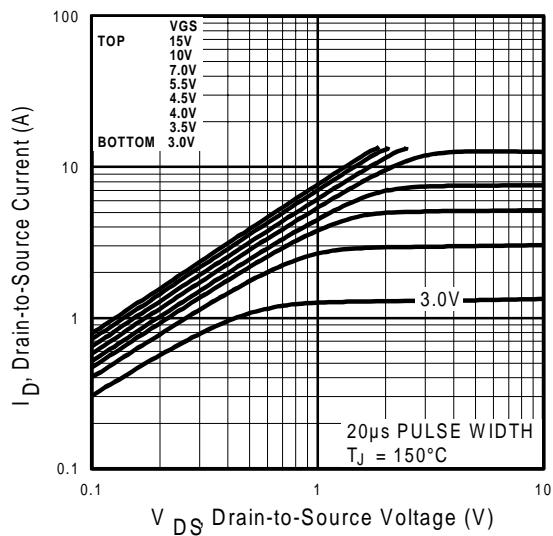


Fig 2. Typical Output Characteristics

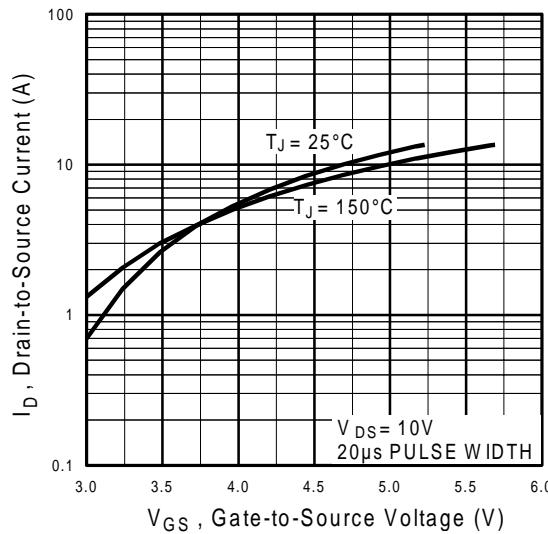


Fig 3. Typical Transfer Characteristics

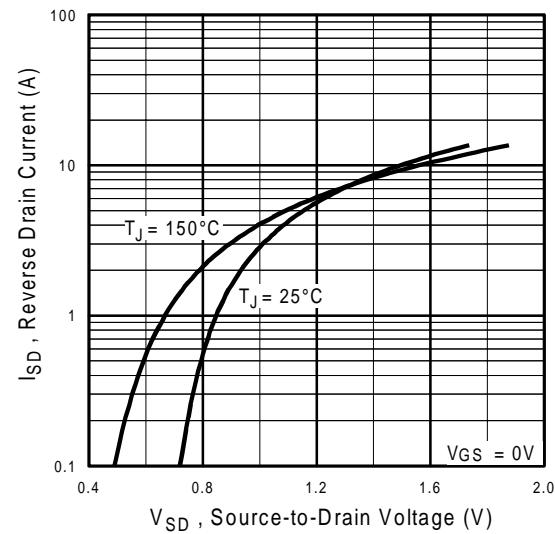


Fig 4. Typical Source-Drain Diode Forward Voltage

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Power Mosfet Characteristics

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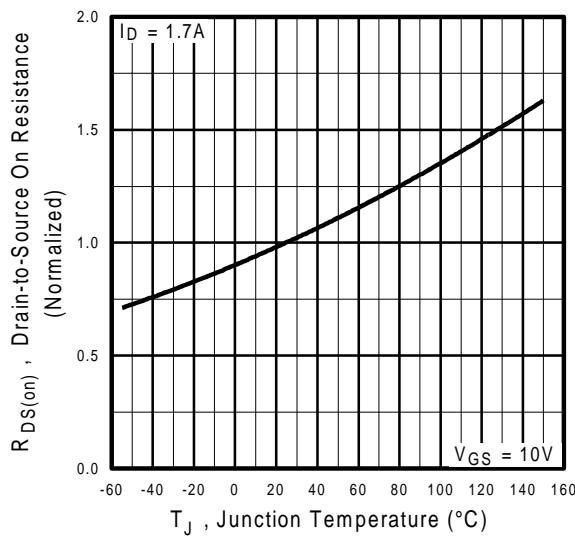


Fig 5. Normalized On-Resistance Vs. Temperature

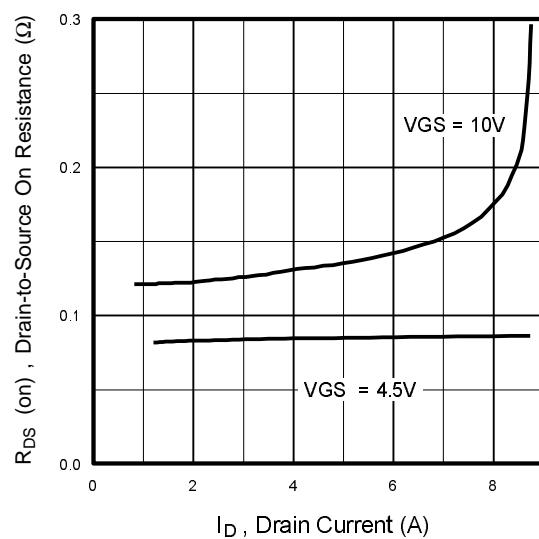


Fig 6. Typical On-Resistance Vs. Drain Current

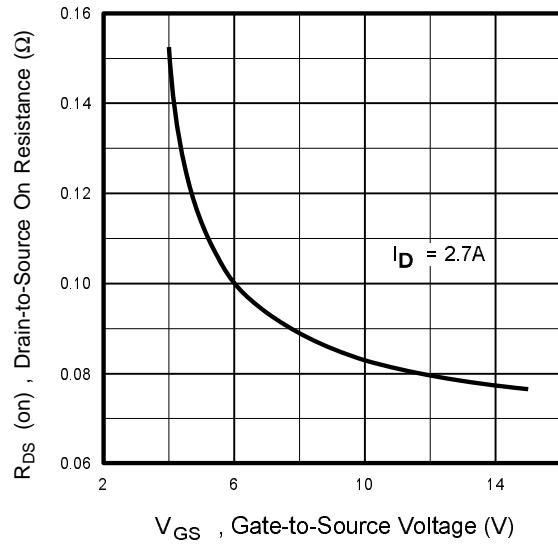


Fig 7. Typical On-Resistance Vs. Gate Voltage

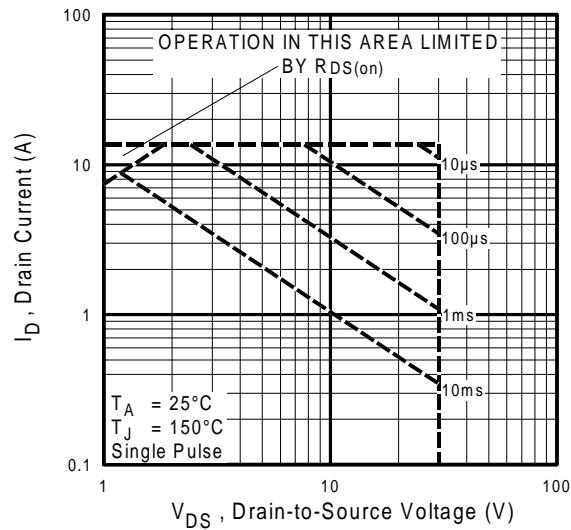


Fig 8. Maximum Safe Operating Area

Power Mosfet Characteristics

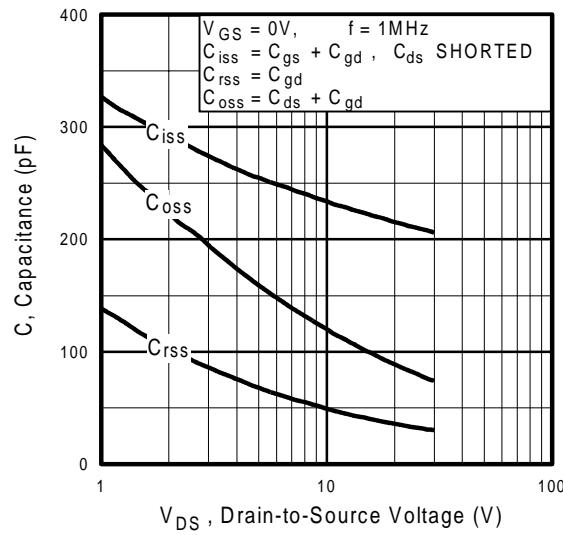


Fig 9. Typical Capacitance Vs.
Drain-to-Source Voltage

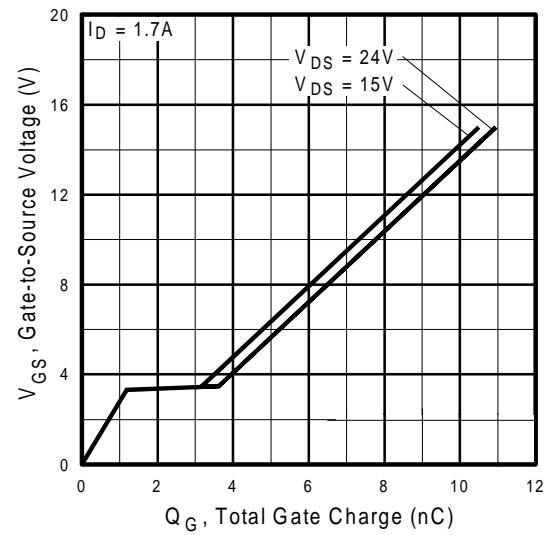


Fig 10. Typical Gate Charge Vs.
Gate-to-Source Voltage

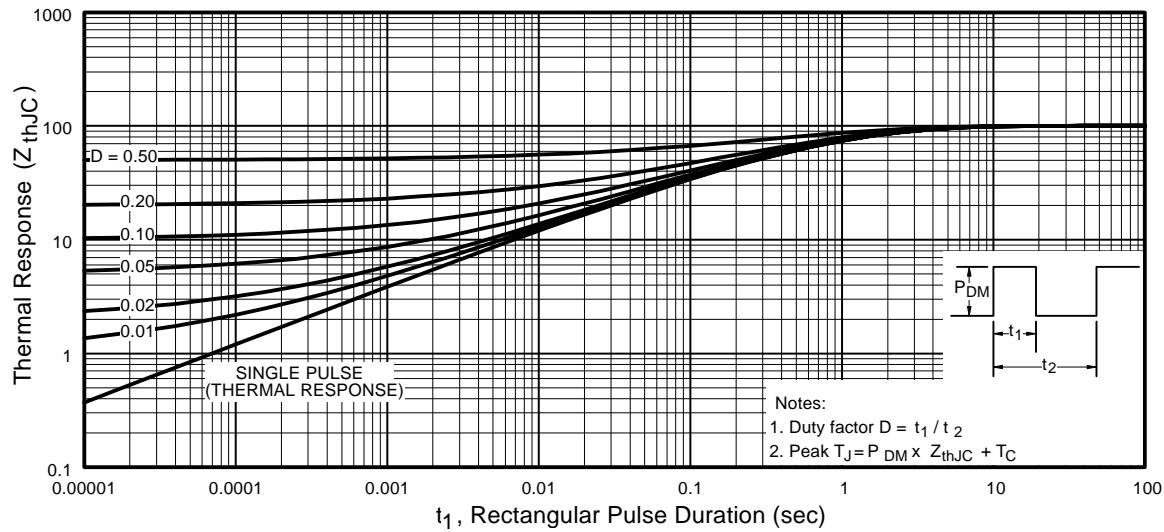


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

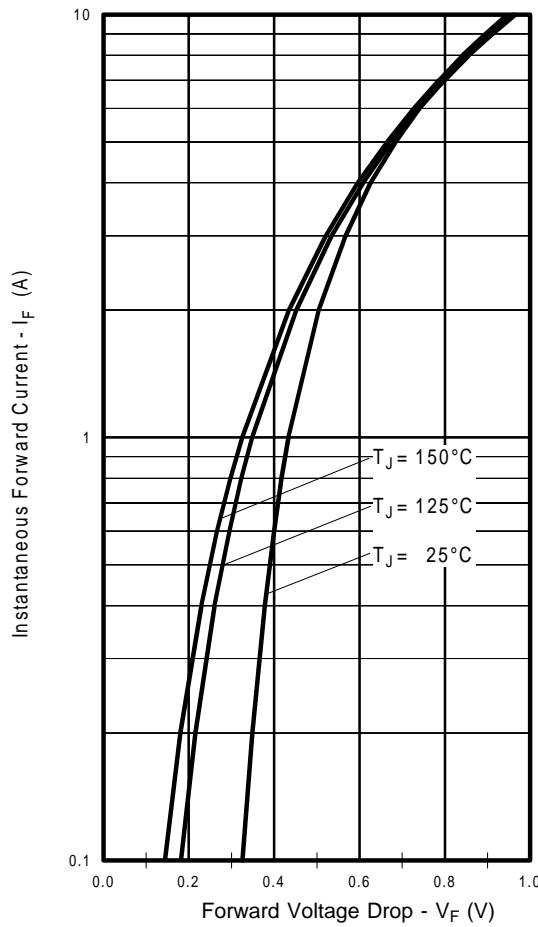
Schottky Diode Characteristics

Fig. 12 -Typical Forward Voltage Drop Characteristics

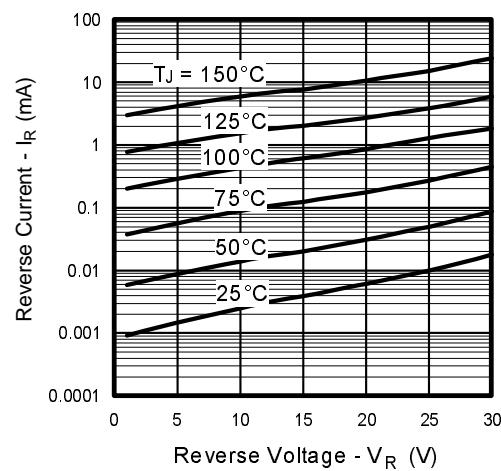


Fig. 13 - Typical Values of Reverse Current Vs. Reverse Voltage

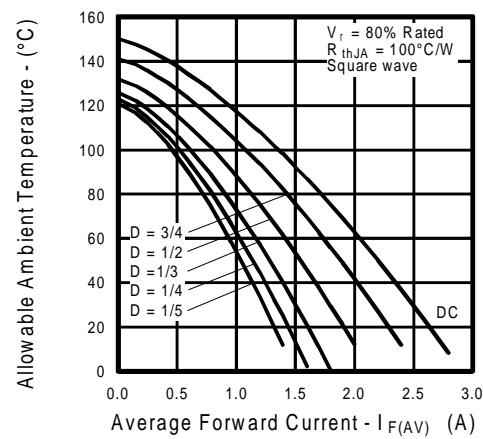
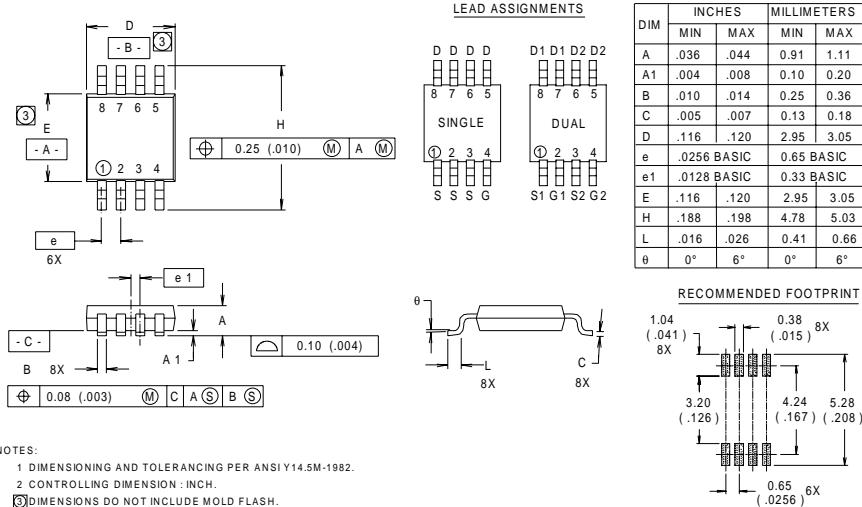


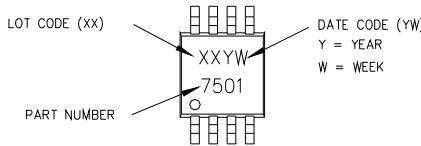
Fig.14 - Maximum Allowable Ambient Temp. Vs. Forward Current

Micro8™ Package Details



Part Marking

EXAMPLE: THIS IS AN IRF7501



WW = (1-26) IF PRECEDED BY LAST DIGIT OF CALENDAR YEAR

YEAR	Y	WORK WEEK	W
2001	1	01	A
2002	2	02	B
2003	3	03	C
1994	4	04	D
1995	5		
1996	6		
1997	7		
1998	8		
1999	9		
2000	0	24	X
		25	Y
		26	Z

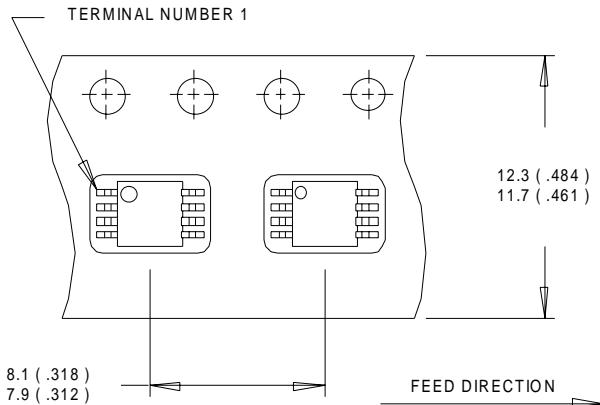
WW = (27-52) IF PRECEDED BY A LETTER

YEAR	Y	WORK WEEK	W
2001	A	27	A
2002	B	28	B
2003	C	29	C
1994	D	30	D
1995	E		
1996	F		
1997	G		
1998	H		
1999	J		
2000	K	50	X
		51	Y
		52	Z

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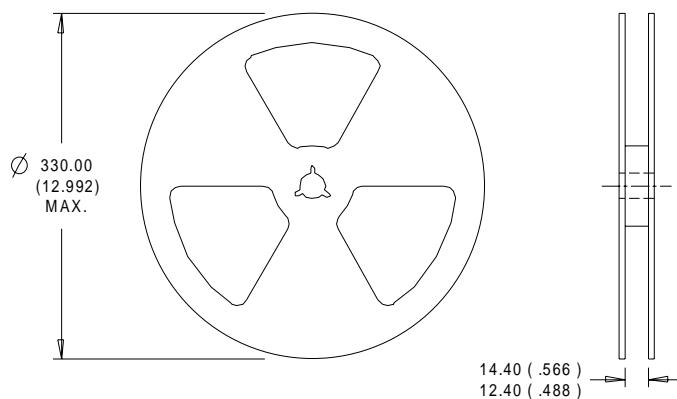
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Micro8™ Tape & Reel



NOTES:

1. OUTLINE CONFORMS TO EIA-481 & EIA-541.
2. CONTROLLING DIMENSION : MILLIMETER.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

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